



Crystallographic Defects and Mechanical Strength of Micron Size Monocrystalline Diamond

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Outline

- Introduction
- Experimental Techniques
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Crystallographic Defects of Diamond



- Crystallographic defects or crystal growth defects of diamond are the result of the nucleation and crystal growth processes that govern the catalytic high pressure-high temperature (HPHT) graphite to diamond transformation (so called diamond synthesis process)
- Crystallographic defects (substitutional or interstitial impurities, vacancies, dislocations, etc.), are sources of mechanical stresses, thus contributing to mechanical strength and fracture characteristics of monocrystalline diamond particles



Crystallographic Defects of Diamond



- The intrinsic properties of diamond crystals are determined by the particularities of the catalytic HP-HT synthesis process; mainly the nucleation & growth rates
- For a given graphite-metal catalyst system the kinetics of the diamond synthesis process (nucleation & growth rates) is controlled via thermodynamic parameters pressure & temperature
 - Low nucleation & growth rates → diamond crystals with low level of crystal growth (CG) defects → high mechanical strength
 - High nucleation & growth rates → diamond crystals with high level of crystal growth (CG) defects → low mechanical strength



Micron Size Monocrystalline Diamond



- Most micron size monocrystalline diamond powders are produced by size reduction (milling) of mesh size diamond powders (starting mesh diamond powder feed)
- Following the micronizing process (mechanical, chemical, and thermal process steps):
 - A large number of the *initial crystal growth (CG) defects* of the starting mesh diamond powder feed *are released*
 - Some of the initial crystal growth (CG) defects of the starting mesh diamond powder feed are transmitted to the resultant micron size diamond powder as residual crystal growth (RCG) defects



Mechanical Strength of Diamond

- Mechanical strength of diamond particle characterizes its ability to resist fracture under static or dynamic (impact) loading
- Mechanical strength of monocrystalline diamond particle is dependent upon particle size, particle shape and concentration of residual crystal growth (RCG) defects





- For a given size and shape, the mechanical strength of a micron size monocrystalline diamond particle is directly related to the concentration of residual crystal growth (RCG) defects:

 - High concentration of RCG defects Low mechanical strength





DR-FTIR Spectroscopy

- The concentration of crystallographic defects of micron size monocrystalline diamond powders was gauged using the Diffuse Reflectance Fourier Transform Infrared (DR-FTIR) Spectroscopy



Fig. 1 – Schematic view of FTIR transmission spectroscopy with a diffuse reflectance accessory $^{\ 8}$



DR-FTIR Spectroscopy



- Diffuse reflectance FTIR is a technique well suited for analysis of powder samples that can give quantitative and qualitative information about the nature and level of impurities and crystalline defects
- FTIR transmittance is related to elastic light scattering due to crystallographic defects such as dislocations and grain boundaries



DR-FTIR Spectrum of Diamond

- ✤ 2670 to 1600 cm-1 represents transmittance from the C=C bonding
- ✤ 1400 to 1050 cm-1 contains peaks due to Nitrogen defects:
 - A centers, B centers, C centers (single substitutional N at 1130 & 1344 cm-1) and platelets



Fig. 2 – DR-FTIR spectrum of diamond



 \clubsuit Different μ size diamond powder types sharing "identical" size

- 6-12 μ m HQ-MB = High quality metal bond diamond
- 6-12 μm LQ-MB = Low quality metal bond diamond



Fig. 3 – Images of diamond samples



- FTIR baseline transmittance
 - FTIR baseline transmittance mirrors the concentration of crystallographic defects (residual crystal growth defects) of micron size monocrystalline diamond powders the higher the concentration of crystallographic defects, the lower the baseline transmittance



Fig. 5 – Overlay of FTIR baseline transmittance of 6-12 μm diamond samples



Crystallographic Defects & FTIR Baseline

- RB diamond sample which possesses intrinsically high concentration of crystallographic defects, exhibits a much lower FTIR baseline transmittance compared to MB diamond samples
- MB diamond samples possess much lower concentration of crystallographic defects and, consequently, exhibit much higher FTIR baseline transmittance
- FTIR baseline transmittance represents a good measure for the concentration of crystallographic defects in micron size monocrystalline diamond powders



- Different quality µ size metal bond (MB) diamond powder sharing "identical" particle size & shape
 - 12-22 μm HQ-MB = high quality metal bond diamond
 - 12-22 μm LQ-MB = low quality metal bond diamond



11288	R0206
LQ-MB	HQ-MB
4884	4541
0.710	0.704
195	179
3.99%	3.94%
11200	DODOC
11288	R0206
LQ-MB	HQ-MB
12.94	12.79
15.32	15.41
18.55	19.70
24.51	25.66
26.95	29.33
	11288 LQ-MB 4884 0.710 195 3.99% 11288 LQ-MB 12.94 15.32 18.55 24.51 26.95

Fig. 6 – PSD overlay

Table 1 – Particle shape & size data



 FTIR spectroscopy results on different quality μ size metal bond (MB) diamond powder sharing "identical" particle size & shape



Fig. 7 – Overlay of FTIR spectra of 12-22 μm diamond samples



Substitutional Nitrogen Impurities in Synthetic Diamond

Substitutional Nitrogen impurities in synthetic diamond (Type Ib)

- It is known that the amount and defect type of substitutional nitrogen in synthetic diamond strongly influences crystal strength
- ✤ Generally, the concentration of the substitutional Nitrogen impurities in the type Ib diamond is proportional to the intensity of the band at 1130 cm-1
- The substitutional N defect (SND) concentration is calculated as the ratio of the percent transmission of the diamond peak (at 2160cm-1) and the single N defect peak (at 1130cm-1) as follows:

SND = (% transmission @ 2160 cm-1) / (% transmission @ 1130 cm-1)



FTIR baseline transmittance and substitutional Nitrogen defect









- South 12-22 μm HQ-MB and LQ-MB diamond samples show similar concentration of the substitutional Nitrogen defect
- There is a noticeable difference between the baseline transmittance of the two diamond samples, with HQ-MB diamond exhibiting a higher baseline transmittance and therefore, lower concentration of crystallographic defects



Raman Spectroscopy

- Macro Raman spectroscopy to complement FTIR spectroscopy
 - The change in the Raman intensity may be caused by increase in the elastic (Rayleigh) scattering of light from crystallographic defects
 - More defects such as lattice dislocations would tend to elastically scatter more of the incident beam and reduce the inelastically scattered Stokes or anti-Stokes Raman scattering



Fig. 9 – Schematic view of Raman spectroscopy



Raman Spectroscopy – Results

 Raman spectroscopy results on different quality μ size metal bond (MB) diamond powder sharing "identical" particle size & shape









FTIR & Raman Spectroscopy – Results

Correlation between FTIR baseline transmittance & Raman diamond peak



Fig. 11 – FTIR & Raman Spectroscopy results of 12-22 μm diamond samples

** The macro Raman spectroscopy results on same diamond powders (12-22 μ m HQ-MB and 12-22 μ m LQ-MB) show that the change in intensity of the diamond peak at 1332 cm-1, correlates well with FTIR base line transmittance 21

INTERTECH 2013 Crushing Strength Testing of μ Size Diamond





Fig. 12 – Crushing strength apparatus (US Patent 7,275,446)



Fig. 13 – Schematic representation of the crushing strength testing



Crushing Strength Index (CSI)

CSI = ROS/IOS x 100



Fig. 14 – PSD overlay of uncrushed and crushed diamond powder (example) ²³

IOS: initial number of on-size particles (50-95% of number distribution before crushing) **ROS**: resulting number of on-size particles (50-95% of number distribution after crushing)



CSI of different quality μ size metal bond (MB) diamond powder sharing "identical" particle size & shape





FTIR baseline transmittance & CSI of different quality µ size metal bond (MB) diamond powder sharing "identical" particle size &





Fig. 16 – Correlation between FTIR baseline transmittance and crushing strength index (CSI) of 12-22 μm diamond samples



- Experimental results established that the FTIR baseline transmittance represents a good measure of the concentration of crystallographic defects, which (for a given particle shape and particle size distribution) is directly related to the mechanical strength of micron size monocrystalline diamond powders
 - HQ-MB micron diamond powder exhibits higher FTIR baseline transmittance (BT), which indicates lower concentration of crystallographic defects. Mechanical strength expressed as crushing strength index (CSI) is higher
 - LQ-MB micron diamond powder exhibits lower FTIR baseline transmittance (BT), which indicates higher concentration of crystallographic defects. Mechanical strength expressed as crushing strength index (CSI) is lower



✤ Different µ size diamond powder types sharing similar (?) size

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Fig. 17 – PSD overlay of 30-40 μm diamond samples



 \clubsuit FTIR spectroscopy results on different μ size diamond powder types





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Experimental Results

Different μ size diamond powder types sharing "similar" particle size & shape
24 30-40 H02-MB #M3





Particle Shape Data	30-40 HQ2-MB	30-40 MQ1-MB	30-40 RB3
Total Particle Count	4677	4895	4761
Average Aspect Ratio (Mean)	0.724	0.711	0.718
Number Particles with AR < 0.5	139	153	141
Number Particles with AR < 0.5 (%)	2.97%	3.13%	2.96%
Particle Size Data			
Equivalent Spherical Diameter (ESD)	30-40 HQ2-MB	30-40 MQ1-MB	30-40 RB3
5%	34.88	33.75	33.86
50%	40.25	38.74	40.86
95%	46.21	44.973	49.07
99.9%	52.97	53.63	59.98
Max Particle	55.21	61.65	68.44

Fig. 19 – PSD overlay of 30-40 mm diamond samples

FTIR spectroscopy results on different μ size diamond powder types sharing "similar" particle size & shape

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Experimental Results



Fig. 20 – Overlay of FTIR spectra of 30-40 μ m diamond samples



CSI of different μ size diamond powder types sharing "similar" particle size & shape



Fig. 20 – Crushing Strength Index (CSI) of 30-40 μm diamond samples



Summary

The objective of this work was to investigate the correlation, between the concentration of crystallographic defects of micron size monocrystalline diamond powders and their mechanical strength

Experimental results showed that the FTIR baseline transmittance of micron size monocrystalline diamond powders represents a good measure of the concentration of crystallographic defects (residual crystal growth defects) which (for a given particle shape and size distribution) is directly related to their mechanical strength, expressed as crushing strength index (CSI)



Conclusions

- High quality metal bond micron diamond powder (produced from high quality mesh diamond powder feed), exhibits increased FTIR baseline transmittance, which indicates low concentration of crystallographic defects and, consequently, high mechanical strength
- Low quality metal bond micron diamond powder (produced from low quality mesh diamond powder feed), exhibits lower FTIR baseline transmittance which indicates higher concentration of crystallographic defects and, therefore lower mechanical strength
- Resin bond micron diamond powder (produced from resin bond mesh diamond powder feed), exhibits lowest FTIR baseline transmittance, which indicates highest concentration of crystallographic defects and, accordingly, lowest mechanical strength



Thank you!

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